

Approval Sheet

Customer	
Product Number	M5UV-BGM2450P-A
Data Rate	4800 MT/s
Pin	288 pin
CI-tRCD-tRP	40-39-39
Operating temperature	Tc=-40 to 95°C
Date	21 th March 2023

Rev 1.0

1. Features

- JEDEC Standard 288-pin Dual In-Line Memory Module
- VDD=VDDQ= 1.1V (1.067V ~ 1.166V)
- VPP=1.8V (1.746V ~ 1.908V)
- VDDSPD= 1.8V
- On-die, internal, adjustable VREF generation for DQ,CA,CS
- 16n-bit prefetch
- Two independent I/O sub channels
- Programmable /CAS Latency: 22,26,28,30,32,36,40,42
- tREFI 3.9us for -40°C ≤Tcase < 85°C, tREFI 1.95us for 85°C < Tcase ≤ 95°C
- On-Die ECC
- PMIC on DIMM, nominal supply 5V, VIN_Bulk input supply range: 4.25 V to 5.5 V
- Fly-by topology
- I3C/I2C support
- Terminated control and C/A bus
- SPD EEPROM Hub and Integrated Thermal Sensor
- Halogen-free

Specification

Density	Data Rate	IC Configuration	DIMM Organization	Number of IC	Number of rank	Side	ECC
32GB	4800 MT/s	2Gx8 (16Gb)	4Gx64	16	2	2	N

Key timing parameters

tCK (ns)	tRCD (ns)	tRP (ns)	tRAS (ns)	tRC (ns)
0.416	16.00	16.00	32	48.00

tRFC parameter by IC Configuration

Parameter	IC Configuration				Unit
	8Gb	16Gb	24Gb	32Gb	
tRFC1,min	195	295	TBD	TBD	ns
tRFC2,min	130	160	TBD	TBD	ns
tRFCsb,min	115	130	TBD	TBD	ns

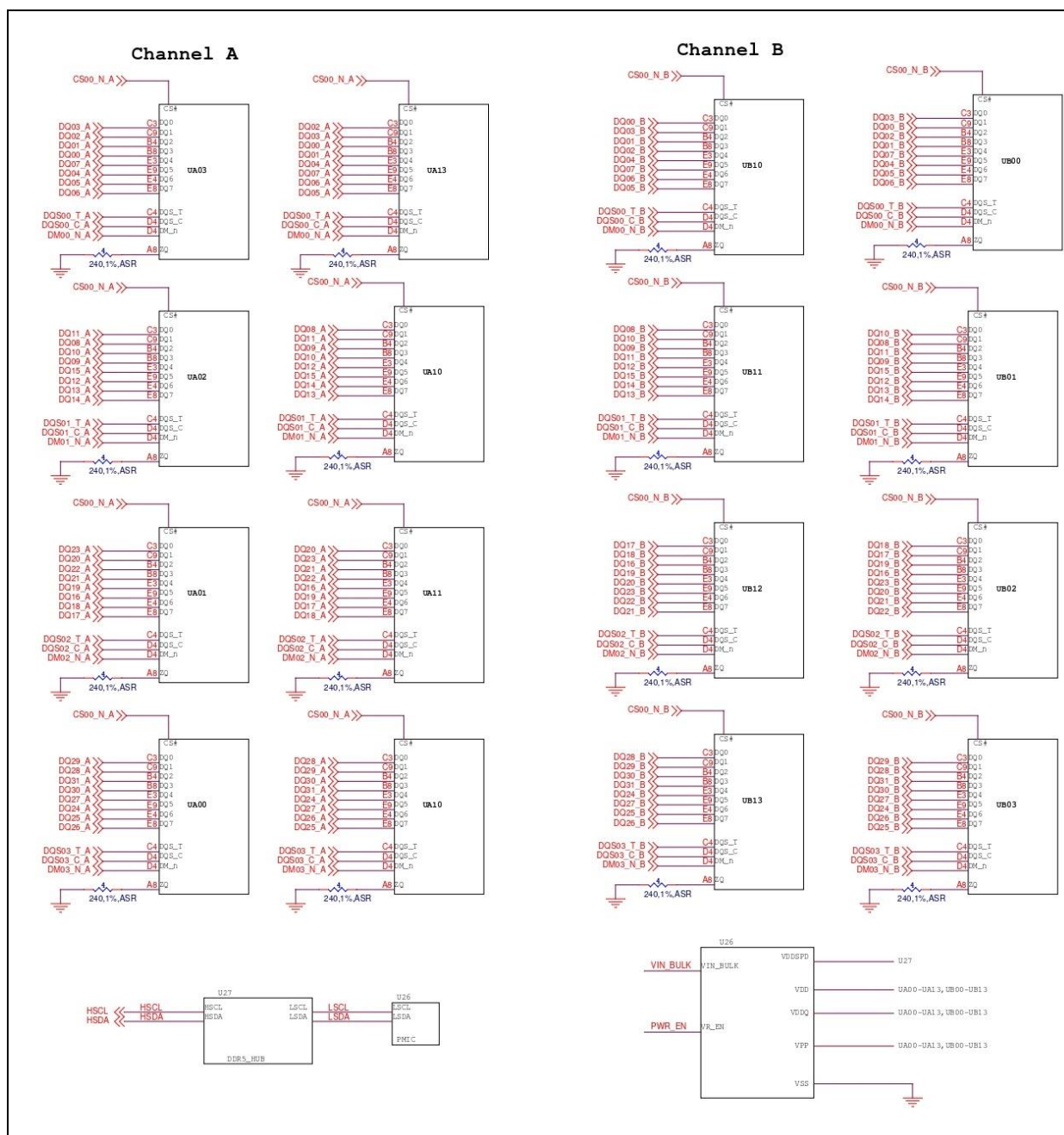
2. Pin Assignments

288-Pin DDR5 UDIMM Front								288-Pin DDR5 UDIMM Back							
Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol	Pin	Symbol
1	VIN_BULK	37	DQ20_A	73	CK0_A_c	109	Vss	145	VIN_BULK	181	DQ22_A	217	CK1_A_c	253	Vss
2	RFU	38	Vss	74	Vss	110	DQ5_B	146	VIN_BULK	182	Vss	218	Vss	254	DQ7_B
3	RFU	39	DQ21_A	75	RFU	111	Vss	147	PWR_GOOD	183	DQ23_A	219	RFU	255	Vss
4	HSCL	40	Vss	76	RFU	112	DQ8_B	148	HAS	184	Vss	220	RFU	256	DQ10_B
5	HSDA	41	DQ24_A	77	Vss	113	Vss	149	RFU	185	DQ26_A	221	Vss	257	Vss
6	Vss	42	Vss	78	CK0_B_t	114	DQ9_B	150	Vss	186	Vss	222	CK1_B_t	258	DQ11_B
7	RFU	43	DQ25_A	79	CK0_B_c	115	Vss	151	PWR_EN	187	DQ27_A	223	CK1_B_c	259	Vss
8	Vss	44	Vss	80	Vss	116	DM1_B_n	152	RFU	188	Vss	224	Vss	260	DQS1_B_c
9	DQ0_A	45	DM3_A_n	81	RFU	117	Vss	153	Vss	189	DQS3_A_c	225	RFU	261	DQS1_B_t
10	Vss	46	Vss	82	CA12_B	118	DQ12_B	154	DQ2_A	190	DQS3_A_t	226	RFU	262	Vss
11	DQ1_A	47	DQ28_A	83	Vss	119	Vss	155	Vss	191	Vss	227	Vss	263	DQ14_B
12	Vss	48	Vss	84	CA10_B	120	DQ13_B	156	DQ3_A	192	DQ30_A	228	CA11_B	264	Vss
13	DQS0_A_c	49	DQ29_A	85	CA8_B	121	Vss	157	Vss	193	Vss	229	CA9_B	265	DQ15_B
14	DQS0_A_t	50	Vss	86	Vss	122	DQ16_B	158	DM0_A_n	194	DQ31_A	230	Vss	266	Vss
15	Vss	51	CB0_A	87	CA6_B	123	Vss	159	Vss	195	Vss	231	CA7_B	267	DQ18_B
16	DQ4_A	52	Vss	88	CA4_B	124	DQ17_B	160	DQ6_A	196	CB2_A	232	CA5_B	268	Vss
17	Vss	53	CB1_A	89	Vss	125	Vss	161	Vss	197	Vss	233	Vss	269	DQ19_B
18	DQ5_A	54	Vss	90	CA2_B	126	DQS2_B_c	162	DQ7_A	198	CB3_A	234	CA3_B	270	Vss
19	Vss	55	DQS4_A_c	91	CA0_B	127	DQS2_B_t	163	Vss	199	Vss	235	CA1_B	271	DM2_B_n
20	DQ8_A	56	DQS4_A_t	92	Vss	128	Vss	164	DQ10_A	200	ALERT_n	236	Vss	272	Vss
21	Vss	57	Vss	93	CS0_B_n	129	DQ20_B	165	Vss	201	Vss	237	CS1_B_n	273	DQ22_B
22	DQ9_A	58	CS0_A_n	94	Vss	130	Vss	166	DQ11_A	202	CS1_A_n	238	Vss	274	Vss
23	Vss	59	Vss	95	RESET_n	131	DQ21_B	167	Vss	203	Vss	239	DQS4_B_c	275	DQ23_B
24	DM1_A_n	60	CA0_A	96	Vss	132	Vss	168	DQS1_A_c	204	CA1_A	240	DQS4_B_t	276	Vss
25	Vss	61	CA2_A	97	CB0_B	133	DQ24_B	169	DQS1_A_t	205	CA3_A	241	Vss	277	DQ26_B
26	DQ12_A	62	Vss	98	Vss	134	Vss	170	Vss	206	Vss	242	CB2_B	278	Vss
27	Vss	63	CA4_A	99	CB1_B	135	DQ25_B	171	DQ14_A	207	CA5_A	243	Vss	279	DQ27_B
28	DQ13_A	64	CA6_A	100	Vss	136	Vss	172	Vss	208	CA7_A	244	CB3_B	280	Vss
29	Vss	65	Vss	101	DQ0_B	137	DM3_B_n	173	DQ15_A	209	Vss	245	Vss	281	DQS3_B_c
30	DQ16_A	66	CA8_A	102	Vss	138	Vss	174	Vss	210	CA9_A	246	DQ2_B	282	DQS3_B_t
31	Vss	67	CA10_A	103	DQ1_B	139	DQ28_B	175	DQ18_A	211	CA11_A	247	Vss	283	Vss
32	DQ17_A	68	Vss	104	Vss	140	Vss	176	Vss	212	Vss	248	DQ3_B	284	DQ30_B
33	Vss	69	CA12_A	105	DQS0_B_c	141	DQ29_B	177	DQ19_A	213	RFU	249	Vss	285	Vss
34	DQS2_A_c	70	RFU	106	DQS0_B_t	142	Vss	178	Vss	214	RFU	250	DM0_B_n	286	DQ31_B
35	DQS2_A_t	71	Vss	107	Vss	143	RFU	179	DM2_A_n	215	Vss	251	Vss	287	Vss
36	Vss	72	CK0_A_t	108	DQ4_B	144	RFU	180	Vss	216	CK1_A_t	252	DQ6_B	288	RFU

3. Pin Descriptions

Symbol	Type	I/O Level	Description	Symbol	Type	I/O Level	Description
CK_t, CK_c	Input	VDDQ	Clock	DQ[31:0]_A DQ[31:0]_B	Input/ Output	VDDQ	Data Input/Output
CA[12:0]_A CA[12:0]_B	Input	VDDQ	Command/Address Inputs	CB[3:0]_A CB[3:0]_B	Input/ Output	VDDQ	ECC Check Bits Input/Output
CS[1:0]_A CS[1:0]_B	Input	VDDQ	Chip Select	DQS[4:0]_A_t DQS[4:0]_B_t	Input/ Output	VDDQ	Data Strobe
ALERT_n	Output	VDDQ	Alert	DQS[4:0]_A_c DQS[4:0]_B_c	Input/ Output	VDDQ	Data Strobe
RESET_n	CMOS Input	VDDQ	Active Low Asynchronous Reset	DM[3:0]_A_n DM[3:0]_B_n	Input	VDDQ	Input Data Mask
PWR_GOOD	Input/ Output	VDDQ	Power Good Indicator	VIN_BULK	Supply		External Power Supply
HSCL	Input	VOUT	Host Sideband Bus Clock	PWR_EN	Input		PMIC Enable
HSDA	Input/ Output	VOUT	Host Sideband Bus Data	VSS	Supply		Ground
HSA	Input	GND	Host Sideband Bus Device ID	RFU			Reserved for future use

4. Function Block Diagram



5. Thermal Characteristics

Symbol	Parameter		Rating	Units	Note
T _C	Operation Temperature	Normal Operating Temp.	-40 to 85	°C	1,2,3
		Extended Temp.	85 to 95	°C	1,2,3,4
T _{STG}	Storage Temperature		-55 to 100	°C	5

Note:

- Maximum operating case temperature; T_C is measured in the center of the package.
- A thermal solution must be designed to ensure the DRAM device does not exceed the maximum T_C during operation.
- Device functionality is not guaranteed if the DRAM device exceeds the maximum T_C during operation.
- If T_C exceeds 85°C, the DRAM must be refreshed externally at 2X refresh, which is a 1.95μs interval refresh rate.
- Storage temperature is defined as the temperature of the top/center of the DRAM and does not reflect the storage temperatures of shipping trays.

6. IDD, IDDQ and IPP Specifications

Symbol	Description	Value (Typical)		Units
		IDD Max.	IPP Max.	
IDD0	Operating One Bank Active-Precharge Current	1560	112	mA
IDD0F	Operating Four Bank Active-Precharge Current	1872	128	mA
IDD2N	Precharge Standby Current	1472	96	mA
IDD2P	Precharge Power-Down Current	1408	96	mA
IDD3N	Active Standby Current	2272	112	mA
IDD3P	Active Power-Down Current	2272	112	mA
IDD4R	Operating Burst Read Current	3752	120	mA
IDD4W	Operating Burst Write Current	3528	344	mA
IDD5B	Burst Refresh Current (Normal Refresh Mode)	2952	272	mA
IDD5C	Burst Refresh Current (Same Bank Refresh Mode)	1816	144	mA
IDD6N	Self Refresh Current: Normal Temperature Range	1632	240	mA
IDD7	Operating Bank Interleave Read Current	4752	232	mA
IDD8	Maximum Power Saving Deep Power Down Current	1280	96	mA

The above information may be change due to the update of the device specifications and is for reference only.

7. Timing Parameters

Parameter	Symbol	4400		4800		5200		Unit
		Min	Max	Min	Max	Min	Max	
Clock Timing								
Average clock period	tCK,AVG	0.454		0.416		0.384		ns
Command and Address Timing								
Read to Read command delay for same bank group	tCCD_L	8nCK,5ns (MAX)		8nCK,5ns (MAX)		8nCK,5ns (MAX)		nCK
WRITE to WRITE command delay for same bank group	tCCD_L_WR	32nCK, 20ns (MAX)		32nCK, 20ns (MAX)		32nCK, 20ns (MAX)		nCK
WRITE to WRITE command delay for same bank group, second WRITE not RMW	tCCD_L_WR2	16nCK, 10ns (MAX)		16nCK, 10ns (MAX)		16nCK, 10ns (MAX)		nCK
Read to Read or Write to Write command delay for different bank group for BL16, BC8 OTF	tCCD_S	8		8		8		nCK
ACTIVATE to ACTIVATE command delay to different bank group for 2KB page size	tRRD_S,2K	8		8		8		nCK
ACTIVATE to ACTIVATE command delay to different bank group for 1KB page size	tRRD_S,1K	8		8		8		nCK
ACTIVATE to ACTIVATE command delay to same bank group for 2KB page size	tRRD_L,2K	8nCK,5ns (MAX)		8nCK,5ns (MAX)		8nCK,5ns (MAX)		nCK
ACTIVATE to ACTIVATE command delay to same bank group for 1KB page size	tRRD_L,1K	8nCK,5ns (MAX)		8nCK,5ns (MAX)		8nCK,5ns (MAX)		nCK
Four activate window for	tFAW,2K	40nCK,		40nCK,		40nCK,		ns

2KB page size		18.160ns (MAX)		16.640ns (MAX)		15.360ns (MAX)		
Four activate window for 1KB page size	tFAW,1K	32nCK, 14.528ns (MAX)		32nCK, 13.312ns (MAX)		32nCK, 12.288ns (MAX)		ns
Delay from start of internal WRITE transaction to internal READ command for different bank group	tWTR_S	4nCK, 2.5ns (MAX)		4nCK, 2.5ns (MAX)		4nCK, 2.5ns (MAX)		ns
Delay from start of internal WRITE transaction to internal READ command for same bank group	tWTR_L	16nCK, 10ns (MAX)		16nCK, 10ns (MAX)		16nCK, 10ns (MAX)		ns
Delay from start of internal WRITE transaction to internal READ with AUTO PRECHARGE command for same bank	tWTRA	tWR-tRTP		tWR-tRTP		tWR-tRTP		ns
Internal READ command to PRECHARGE command delay	tRTP	12nCK, 7.5ns (MAX)		12nCK, 7.5ns (MAX)		12nCK, 7.5ns (MAX)		ns
PRECHARGE to PRECHARGE delay	tPPD	2		2		2		nCK
WRITE recovery time	tWR	29.964		29.952		29.952		ns
DLL locking time	tDLLK	1280		1536		1536		nCK
Mode Register Read/Write Timing								
Mode register READ command period	tMRR	14ns, 16nCK (MAX)		14ns, 16nCK (MAX)		14ns, 16nCK (MAX)		
Mode register READ pattern to mode register READ pattern command spacing	tMRR_p	8		8		8		nCK
Mode register WRITE command period	tMRW	5ns,8nCK (MAX)		5ns,8nCK (MAX)		5ns,8nCK (MAX)		
Mode register SET command delay	tMRD	14ns, 16nCK		14ns, 16nCK		14ns, 16nCK		

		(MAX)		(MAX)		(MAX)		
DFE mode register WRITE update delay time	tDFE	80		80		80		ns
Data Strobe Timing								
DQS_t, DQS_c differential READ preamble	tRPRE	TBD		TBD		TBD		tCK
DQS_t, DQS_c differential READ postamble	tRPST	TBD		TBD		TBD		tCK
DQS_t, DQS_c rising edge output timing location from rising CK_t, CK_c	tDQCK	-0.286	0.286	-0.3	0.3	TBD	TBD	tCK
DQS_t, DQS_c rising edge output variance window	tDQCKI		0.475		0.49		TBD	tCK
Data Strobe Timing								
2-tCK WRITE preamble enable window	tWPRE_EN_2 tCK	1.5		1.5		1.5		tCK
3-tCK WRITE preamble enable window	tWPRE_EN_3 tCK	2.5		2.5		2.5		tCK
4-tCK WRITE preamble enable window	tWPRE_EN_4 tCK	2.5		2.5		2.5		tCK
DQS_t, DQS_c differential WRITE postamble	tWPST	TBD		TBD		TBD		tCK
Final trained value of host DQS_t-DQS_c timing relative to CWL CK_t-CK_c edge	tDQSoffset	-0.5	0.5	-0.5	0.5	-0.5	0.5	tCK
Write leveling setup time	tWLS	-80	80	-80	80	-80	80	ps
Write leveling hold time	tWLH	-80	80	-80	80	-80	80	ps
Voltage/temperature drift window of first rising DQS_t preamble edge relative to CWL CK_t-CK_c edge (x4/x8/x16)	tDQSD	-0.25 x tWPRE_E N_ntCK	0.25 x tWPRE_E N_ntCK	-0.25 x tWPRE_E N_ntCK	0.25 x tWPRE_E N_ntCK	-0.25 x tWPRE_E N_ntCK	0.25 x tWPRE_E N_ntCK	tCK
Host and system voltage/ temperature drift window of first rising DQS_t preamble edge relative to	tDQSS	-0.25 x tWPRE_EN_ntCK						tCK

CWL CK_t-CK_c edge (x4/x8/x16)								
MPSM Timing								
MPSM exit to first valid command delay	tMPSMX	tMRD		tMRD		tMRD		ns
ZQ Calibration Timing								
ZQ calibration time	tZQCAL	1		1		1		μs
ZQ calibration latch time	tZQLAT	30ns, 8nCK (MIN)		30ns, 8nCK (MIN)		30ns, 8nCK (MIN)		
Reset Timing								
RESET_n low time for reset initialization with stable power	tPW_RESET	1		1		1		μs
Time after RESET_n assertion to ODT off	tRST_ADC		50		50		50	ns
Self Refresh Timing								
Command pass disable delay	tCPDED	5ns,8nCK (MAX)		5ns,8nCK (MAX)		5ns,8nCK (MAX)		
Self refresh CS_n low pulse width	tCSL	10		10		10		ns
Self refresh exit CS_n high pulse width	tCSH_Srexit	13	30	13	30	13	30	ns
Self refresh exit CS_n low pulse width	tCSL_Srexit	3nCK	30ns	3nCK	30ns	3nCK	30ns	
Self refresh exit CS_n low pulse width with frequency change	tCSL_FreqCh g	VREFCA_ time		VREFCA_ time		VREFCA_ time		ns
Valid clock requirement before SRX	tCKSRX	3.5ns, 8nCK (MAX)		3.5ns, 8nCK (MAX)		3.5ns, 8nCK (MAX)		ns
Valid clock requirement after SRE	tCKLCS	tCPDED + 1nCK		tCPDED + 1nCK		tCPDED + 1nCK		nCK
Self refresh exit CS_n HIGH	tCASRX	0		0		0		ns
Exit self refresh to commands not requiring a	tXS	tRFC1		tRFC1		tRFC1		ns

locked DLL								
Exit self refresh to commands requiring a locked DLL	tXS_DLL	tDLLK		tDLLK		tDLLK		ns
Power-Down Timing								
Command pass disable delay	tCPDED	5ns,8nCK (MAX)		5ns,8nCK (MAX)		5ns,8nCK (MAX)		ns
Power-down time	tPD	7.5ns, 8nCK (MAX)	5*tREFI1 (normal) 9*tREFI2 (FGR)	7.5ns, 8nCK (MAX)	5*tREFI1 (normal) 9*tREFI2 (FGR)	7.5ns, 8nCK (MAX)	5*tREFI1 (normal) 9*tREFI2 (FGR)	ns
Exit power-down to next valid command	tXP	7.5ns, 8nCK (MAX)		7.5ns, 8nCK (MAX)		7.5ns, 8nCK (MAX)		ns
Timing of ACT command to POWER DOWN ENTRY command	tACTPDEN	2		2		2		nCK
Timing of PREab, PREsb or PREpb command to POWER DOWN ENTRY command	tPRPDEN	2		2		2		nCK
Timing of READ or READ w/ AP command to POWER DOWN ENTRY command	tRDPDEN	CL +RBL/2+1		CL +RBL/2+1		CL +RBL/2+1		nCK
Timing of WRITE command to POWER DOWN ENTRY command	tWRPDEN	CWL +WBL/ 2+ (tWR/ tCK(avg)) +1		CWL +WBL/ 2+ (tWR/ tCK(avg)) +1		CWL +WBL/ 2+ (tWR/ tCK(avg)) +1		nCK
Timing of WRITE w/ AP command to POWER DOWN ENTRY command	tWRAPDEN	CWL +WBL/ 2+-0.25 x tWPRES_EN_n tCKWR+1		CWL +WBL/ 2+-0.25 x tWPRES_EN_n tCKWR+1		CWL +WBL/ 2+-0.25 x tWPRES_EN_n tCKWR+1		nCK
Timing of REFab or REFSb command to POWER DOWN ENTRY command	tREFPDEN	2		2		2		nCK
Timing of MRR command	tMRPDEN	CL+8+1		CL+8+1		CL+8+1		nCK

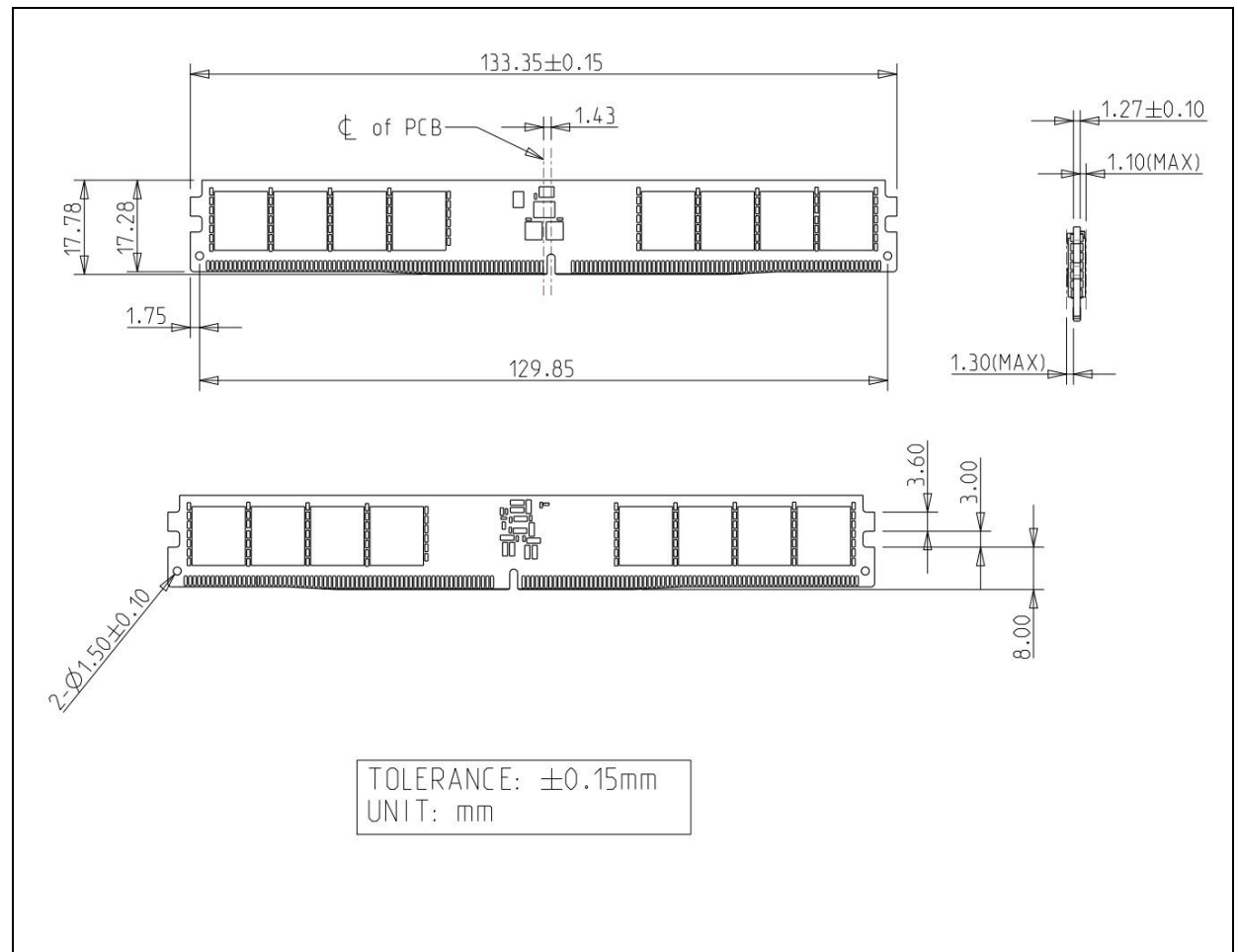
to POWER DOWN ENTRY command								
Timing of MRW command to POWER DOWN ENTRY command	tMRWPDEN	tMRD (MIN)		tMRD (MIN)		tMRD (MIN)		nCK
Timing of MPC command to POWER DOWN ENTRY command	tMPCPDEN	tMPC_delay		tMPC_delay		tMPC_delay		nCK
MPC Command Timing								
MPC to any other valid command	tMPC_Delay	tMRD		tMRD		tMRD		nCK
Time between stable MPC command and first falling CS edge (setup)	tMC_MPC_Se tup	3		3		3		nCK
Time between first rising CS edge and stable MPC command (HOLD)	tMC_MPC_H old	3		3		3		nCK
Time CS_n is held LOW to register MPC command	tMPC_CS	3.5	8	3.5	8	3.5	8	nCK
PDA Timing								
PDA ENUMERATE ID command to any other command cycle	tPDA_DELAY	tPDA_DQ S_DELAY (MAX) + BL/2 + 19ns		tPDA_DQ S_DELAY (MAX) + BL/2 + 19ns		TBD		ns
Delay to rising strobe edge used for sampling DQ during PDA operation	tPDA_DQS_D ELAY	5	18	5	18	TBD	TBD	ns
DQS setup time during PDA operation	tPDA_S	3		3		TBD		nCK
DQS hold time during PDA operation	tPDA_H	3		3		TBD		nCK
Read Training Timing								
Registration of MRW continuous burst mode exit to next valid command delay	tCont_Exit_ Delay		tCont_Exit + tMRW		tCont_Exit + tMRW		tCont_Exit + tMRW	ns
Registration of MRW continuous	tCont_Exit		CL+BL/		CL+BL/		CL+BL/	ns

burst mode exit to			2+10nCK		2+10nCK		2+10nCK	
end of training mode								
Read Preamble Timing								
Delay from MRW command to DQS driven	tSDOn		12nCK, 20ns (MAX)		12nCK, 20ns (MAX)		12nCK, 20ns (MAX)	
Delay from MRW command to DQS disabled	tSDOff		12nCK, 20ns (MAX)		12nCK, 20ns (MAX)		12nCK, 20ns (MAX)	
CA Training Mode Timing								
Registration of CATM entry command to start of training samples time	tCATM_Entry	20		20		20		ns
Registration of CATM exit CS_n assertion to end of training mode (when DQ is no longer driven by the device).	tCATM_Exit		14		14		14	ns
Registration of CATM exit to next valid command delay	tCATM_Exit_ Delay	20		20		20		ns
Time from sample evaluation to output on DQ bus	tCATM_Valid		20		20		20	ns
Time output is available on DQ bus	tCATM_DQ_ Window	2		2		2		nCK
CS_n assertion duration to exit CATM	tCATM_CS_E xit	2	8	2	8	2	8	nCK
Registration of CSTM entry command to start of training samples time	tCSTM_Entry	20		20		20		ns
Min time between last CS_n pulse and first pulse of MPC command to exit CSTM	tCSTM_Min_ to_MPC_exit	4		4		4		nCK
Registration of CSTM exit command to end of training mode	tCSTM_Exit		20		20		20	ns
Time from sample evaluation	tCSTM_Valid		20		20		20	ns

to output on DQ bus								
Time output is available on DQ bus	tCSTM_DQ_ Window	2		2		2		nCK
Registration of CSTM exit to next valid command delay	tCSTM_Exit_ Delay	20		20		20		ns
Write Leveling Timing								
Write leveling pulse enable: time from write leveling training enable MRW to when internal write leveling pulse logic level is valid	tWLPEN	0	15	0	15	0	15	ns
Write leveling output delay	tWLO	0	9.5	0	9.5	0	9.5	ns
Write leveling output error	tWLOE	0	2	0	2	0	2	ns
Width of write leveling internal pulse	tWL_Pulse_ Width	2		2		2		tCK
VREFC/VREFCs Timing								
VREFC/VREFCs command to any other valid command delay	tVREFC_A_Delay/ tVREFC_S_Delay	tMRD		tMRD		tMRD		nCK
Time CS_n is held LOW to register VREFC/VREFCs command	tVREFC_A_CS/ tVREFC_S_CS	3.5	8	3.5	8	3.5	8	nCK
hPPR/sPPR Timing								
hPPR programming time (x4/x8)	tPGMa	1000		1000		1000		ms
hPPR programming time (x16)	tPGMb	2000		2000		2000		ms
sPPR programming time	tPGM_sPPR	CWL +8tCK +tWR		CWL +8tCK +tWR		CWL +8tCK +tWR		tCK
hPPR/sPPR recognition time	tPGM_Exit	tRP		tRP		tRP		ns
hPPR program exit and new address setting time	tPGMPST	50		50		50		μs
sPPR program exit and new address setting time	tPGMPST_sP PR	tMRD		tMRD		tMRD		ns

DQS Interval Oscillator Readout Timing								
Delay time from DQS interval oscillator stop to mode register readout	tOSCO	tMPC_De lay		tMPC_De lay		tMPC_De lay		nCK
DQS interval oscillator start gap in automatic stop mode	tOSCS	tMPC_Delay + DQS interval timer runtime						nCK
ECS Timing								
ECS operation time	tECSc	176nCK, 110ns (MAX)		176nCK, 110ns (MAX)		176nCK, 110ns (MAX)		
CRC Error Reporting Timing								
CRC error to ALERT_n_latency	tCRC_ALERT	3	13	3	13	3	13	ns
CRC ALERT_n pulse width	CRC_ALERT_ PW	12	20	12	20	12	20	nCK

8. Module Dimensions



Note: All dimensions are in millimeters (mils) and should be kept within a tolerance of ± 0.15 (6), unless otherwise specified.

9. RoHS Declaration

innodisk	宜鼎國際股份有限公司 Innodisk Corporation	Page 1/2
Tel: (02) 7703-3000 Internet: https://www.innodisk.com/		
RoHS 自我宣告書 (RoHS Declaration of Conformity)		
Manufacturer Products: All Innodisk EM FLASH, DRAM and EP products		
一、 宜鼎國際股份有限公司（以下稱本公司）特此保證售予貴公司之所有產品，皆符合歐盟 2011/65/EU 及 (EU) 2015/863 關於 RoHS 之規範要求。 Innodisk Corporation declares that all products sold to the company, are complied with European Union RoHS Directive (2011/65/EU) and (EU) 2015/863 requirement.		
二、 本公司同意因本保證書或與本保證書相關事宜有所爭議時，雙方宜友好協商，達成協議。 Innodisk Corporation agrees that both parties shall settle any dispute arising from or in connection with this Declaration of Conformity by friendly negotiations.		
三、 本公司聲明我們的產品符合 RoHS 指令的附件中 7(a)、7(c)-I、6(c) 允許豁免。 We declare, our products permitted by the following exemptions specified in the Annex of the RoHS directive.		
※ 7(a) Lead in high melting temperature type solders (i.e. lead-based alloys containing 85% by weight or more lead).		
※ 7(c)-I Electrical and electronic components containing lead in a glass or ceramic other than dielectric ceramic in capacitors, e.g. piezoelectric devices, or in a glass or ceramic matrix compound.		
※ 6(c) Copper alloy containing up to 4% lead by weight. (This exemption applies to products that use antennas)		
Name of hazardous substance	Limited of RoHS ppm (mg/kg)	
鉛 (Pb)	< 1000 ppm	
汞 (Hg)	< 1000 ppm	
鎘 (Cd)	< 100 ppm	
六價鉻 (Cr 6+)	< 1000 ppm	
多溴聯苯 (PBBs)	< 1000 ppm	
多溴二苯醚 (PBDEs)	< 1000 ppm	
鄰苯二甲酸二(2-乙基己基)酯 (DEHP)	< 1000 ppm	
鄰苯二甲酸丁酯苯甲酯 (BBP)	< 1000 ppm	
鄰苯二甲酸二丁酯 (DBP)	< 1000 ppm	

innodisk

宜鼎國際股份有限公司
Innodisk Corporation

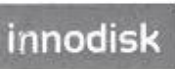
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鄰苯二甲酸二異丁酯 (DIBP)	< 1000 ppm
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立 保 證 書 人 (Guarantor)

Company name 公司名稱: Innodisk Corporation 宜鼎國際股份有限公司Company Representative 公司代表人: Randy Chien 簡川勝Company Representative Title 公司代表人職稱: Chairman 董事長Date 日期: 2021 / 06 / 09

10. REACH Declaration

	宜鼎國際股份有限公司 Innodisk Corporation REACH Declaration
Tel: (02) 7703-3000 Fax: (02) 7703-3555 Internet: https://www.innodisk.com/	
Innodisk Corporation pursues its social responsibility for global environmental preservation by committing to be compliant with REACH regulation (REGULATION (EC) No 1907/2006). We hereby confirm that the product(s),	
Scope: Flash Memory, DRAM Module and Embedded Peripherals Products.	
■ The standard products of not listed in the <u>Appendix2</u> meet the requirements of REACH SVHC regulations (SVHCs < 0.1% in Article), as described in the candidate list table currently including 224 substances and shown on the ECHA website. (http://echa.europa.eu/de/candidate-list-table). ■ The standard products listed in the <u>Appendix2</u> contain(s) one or more hazardous substances or constituents exceeding 0.1 % by weight in article if not otherwise specified in candidate list table. Where the threshold value is exceeded, the substances in question are to be declared in accompanying. (SVHCs > 0.1% in Article). ■ Comply with REACH Annex XVII.	
Guarantor	
Company name 公司名稱: <u>Innodisk Corporation 宜鼎國際股份有限公司</u>	
Company Representative 公司代表人: <u> 陳怡全</u>	
Company Representative Title 公司代表人職稱: <u>QA Manager 品保經理</u>	
Date 日期: <u>2022 / 06 / 14</u>	
	

Revision Log

Rev	Date	Modification
0.1	21 th March 2023	Preliminary Edition
1.0	21 th March 2023	Official release.